

IGBT

TRENCHSTOP[™] IGBT4 High Speed Chip IGC18T120T8Q

Data Sheet

Industrial Power Control

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TRENCHSTOP[™] IGBT4 High Speed Chip

Features:

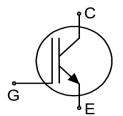
- 1200V trench & field stop technology
- Low switching losses
- Positive temperature coefficient
- Easy paralleling

Recommended for:

• Discrete components

Applications:

- High frequency drives
- Uninterruptible power supplies
- Welding
- Solar inverters



Chip Type	V _{CE}	<i>I</i> _{Cn} ¹	Die Size	Package
IGC18T120T8Q	1200V	15A	4.16mm x 4.34mm	Sawn on foil

Mechanical Parameters

Die size		4.16 x 4.34		
Emitter pad size		See chip drawing	2	
Gate pad size		1.185 x 0.702	mm ²	
Area total		18.05		
Thickness		115	μm	
Wafer size		200	mm	
Maximum possible ch	ips per wafer	1510		
Passivation frontside		Photoimide		
Pad metal	ad metal 3200nm AlSiCu			
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely durir production process		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, ≤500μm		
Reject ink dot size		Ø 0.65mm; max. 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 25°C		
(<6 months)	for open MBB bags	pags Acc. IEC 62258-3; Section 9.4 Storage Environment		

¹ Nominal collector current at T_C =100°C for chip packaged in TO packages, see application example cited on page 5.

L7633S, L7633Q 3 Rev. 2.0, 13.10.2015



Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T _{vj} =25°C	V _{CE}	1200	V
DC collector current, limited by $T_{\rm vj\;max}^{\;\;2}$	I _C	-	Α
Pulsed collector current, t_p limited by $T_{vj \max}$ 3	I _{C,puls}	45	Α
Gate-emitter voltage	V_{GE}	±20	V
Virtual junction operating temperature	T_{vj}	-40 +175	°C
Short circuit data $^{3/4}$ V_{GE} =15V, V_{CC} =800V, T_{vj} =150°C	t _{sc}	10	μs

Static Characteristics (tested on wafer), T_{vi}=25°C

Parameter	Symbol Conditions		Value			Unit	
raiailietei	Symbol	Conditions	min.	typ.	max.		
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V, I_{C} =0.5mA	1200	ı	-		
Collector-emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =15A	1.78	2.05	2.42	V	
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =0.5mA, $V_{\rm GE}$ = $V_{\rm CE}$	5.3	5.8	6.3		
Zero gate voltage collector current	I _{CES}	$V_{\text{CE}} = 1200 \text{V}, \ V_{\text{GE}} = 0 \text{V}$	1	1	2	μA	
Gate-emitter leakage current	I _{GES}	$V_{CE} = 0V, V_{GE} = 20V$	ı	ı	120	nA	
Integrated gate resistor	r _G			none		Ω	

Electrical Characteristics ³

Parameter	Symbol Conditions		Value			Unit
raiametei			min.	typ.	max.	Oilit
Collector-emitter saturation voltage	V _{CEsat}	V_{GE} =15V, I_{C} =15A, T_{vj} =175°C	-	2.70	-	V
Input capacitance	C _{ies}	$V_{\text{CE}}=25\text{V}$	-	875	-	nE
Reverse transfer capacitance	C _{res}	$V_{ m GE}$ =0V, f =1MHz $T_{ m vj}$ =25°C	-	45	-	pF

² Depending on thermal properties of assembly.

³ Not subject to production test - verified by design/characterization.

⁴ Allowed number of short circuits: <1000; time between short circuits: >1s.



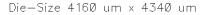
Further Electrical Characteristics

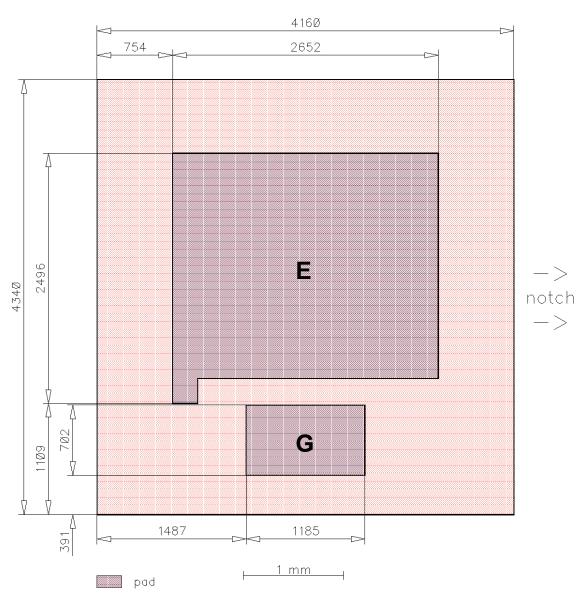
Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	IKW15N120H3	Rev. 1.2
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Chip Drawing





E = Emitter

G = Gate



Bare Die Product Specifics

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

Description	
AQL 0.65 for visual inspection according to failure catalogue	
Electrostatic Discharge Sensitive Device according to MIL-STD 883	

Revision History

Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	13.10.2015

Relevant App	plication Notes



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